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January 2015

FDMC86570LET60

N-Channel Shielded Gate PowerTrench® MOSFET 60 V, 87 A, 4.3 m Ω

Features

- Extended T_J rating to 175°C
- Shielded Gate MOSFET Technology
- Max $r_{DS(on)} = 4.3 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 18 \text{ A}$
- Max $r_{DS(on)}$ = 6.5 m Ω at V_{GS} = 4.5 V, I_D = 15 A
- lacktriangle High performance technology for extremely low $r_{DS(on)}$
- Termination is Lead-free
- RoHS Compliant

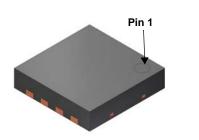


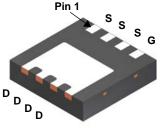
General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench® process that incorporates Shielded Gate technology. This process has been optimized for the on-state resistance and yet maintain superior switching performance.

Application

■ DC-DC Conversion





Bottom

Top Power 33

MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol		Parame	Ratings	Units		
V_{DS}	Drain to Source \	Voltage			60	V
V_{GS}	Gate to Source V	/oltage			±20	V
	Drain Current	-Continuous	T _C = 25 °C	(Note 5)	87	
		-Continuous	T _C = 100 °C	(Note 5)	62	A
ID		-Continuous	T _A = 25 °C	(Note 1a)	18	A
		-Pulsed		(Note 4)	436	
E _{AS}	Single Pulse Ava	lanche Energy		(Note 3)	253	mJ
P _D	Power Dissipatio	n	T _C = 25 °C		65	W
	Power Dissipatio	n	T _A = 25 °C	(Note 1a)	2.8	VV
T _J , T _{STG}	Operating and St	orage Junction Temperat	ure Range		-55 to +175	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	(Note 1)	2.3	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	53	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC86570LT	FDMC86570LET60	Power33	13 "	12 mm	3000 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	60			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		30		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 48 V, V _{GS} = 0 V			1	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	1.0	1.8	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25 °C		-7		mV/°C
		$V_{GS} = 10 \text{ V}, I_D = 18 \text{ A}$		3.1	4.3	
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 15 \text{ A}$		4.7	6.5	mΩ
, ,		$V_{GS} = 10 \text{ V}, I_D = 18 \text{ A}, T_J = 125 \text{ °C}$		5.0	6.9	
9 _{FS}	Forward Transconductance	V _{DD} = 5 V, I _D = 18 A		75		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V - 30 V V - 0 V		4790		pF
C _{oss}	Output Capacitance	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1 MHz		821		pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 1011 12		19		pF
R _g	Gate Resistance		0.1	0.9	2.7	Ω

Switching Characteristics

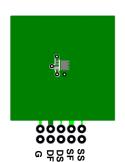
$t_{d(on)}$	Turn-On Delay Time		19	34	ns
t _r	Rise Time	V _{DD} = 30 V, I _D = 18 A,	6.2	12	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$	38	61	ns
t _f	Fall Time		3.9	10	ns
$Q_{g(TOT)}$	Total Gate Charge	V _{GS} = 0 V to 10 V	63	88	nC
$Q_{g(TOT)}$	Total Gate Charge	$V_{GS} = 0 \text{ V to } 4.5 \text{ V}$ $V_{DD} = 30 \text{ V},$	29	41	nC
Q _{gs}	Gate to Source Charge	I _D = 18 A	14		nC
Q_{gd}	Gate to Drain "Miller" Charge		6.3		nC

Drain-Source Diode Characteristics

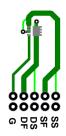
V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 18 \text{ A}$ (Note 2)		0.8	1.3	V
		$V_{GS} = 0 \text{ V}, I_S = 1.9 \text{ A}$ (Note 2)		0.7	1.2	V
t _{rr}	Reverse Recovery Time	L = 19 A di/dt = 100 A/		43	69	ns
Q _{rr}	Reverse Recovery Charge	$I_F = 18 \text{ A, di/dt} = 100 \text{ A/}\mu\text{s}$		26	42	nC

Notes:

^{1.} $R_{\theta JA}$ is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta CA}$ is determined by the user's board design.



 a. 53 °C/W when mounted on a 1 in² pad of 2 oz copper



b. 125 °C/W when mounted on a minimum pad of 2 oz copper

- 2. Pulse Test: Pulse Width < 300 μs , Duty cycle < 2.0%.
- 3. E_{AS} of 253 mJ is based on starting T_{J} = 25 °C, L = 3 mH, I_{AS} = 13 A, V_{DD} = 60 V, V_{GS} = 10 V. 100% test at L = 0.1 mH, I_{AS} = 43 A.
- 4. Pulsed Id please refer to Fig 11 SOA graph for more details.
- 5. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

Typical Characteristics T_J = 25 °C unless otherwise noted

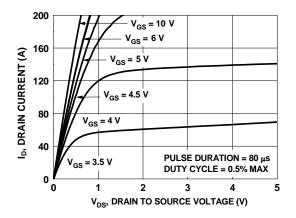


Figure 1. On-Region Characteristics

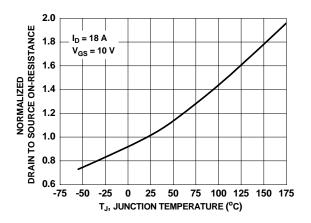


Figure 3. Normalized On-Resistance vs Junction Temperature

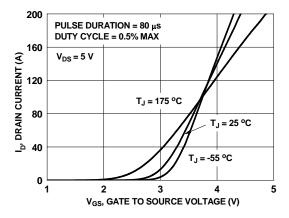


Figure 5. Transfer Characteristics

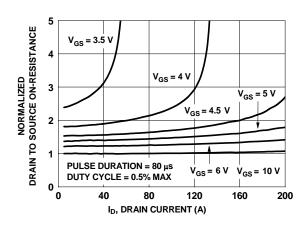


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

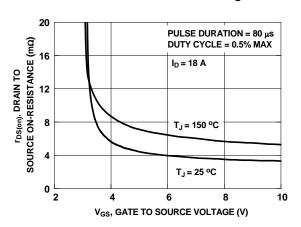


Figure 4. On-Resistance vs Gate to Source Voltage

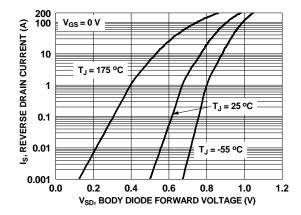


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics $T_J = 25$ °C unless otherwise noted

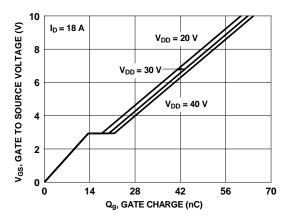


Figure 7. Gate Charge Characteristics

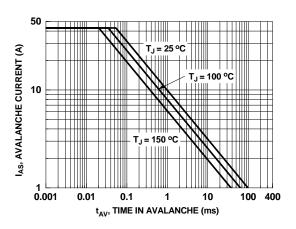


Figure 9. Unclamped Inductive Switching Capability

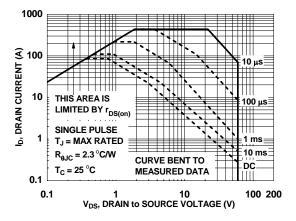


Figure 11. Forward Bias Safe Operating Area

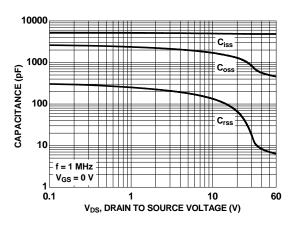


Figure 8. Capacitance vs Drain to Source Voltage

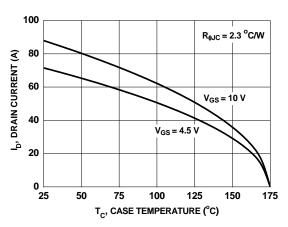


Figure 10. Maximum Continuous Drain Current vs Case Temperature

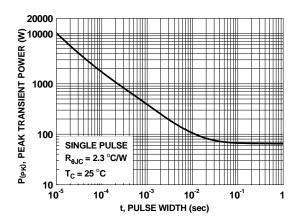


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics $T_J = 25$ °C unless otherwise noted

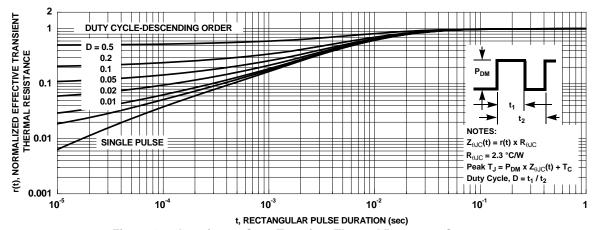
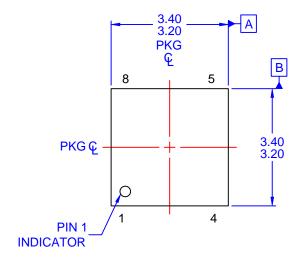
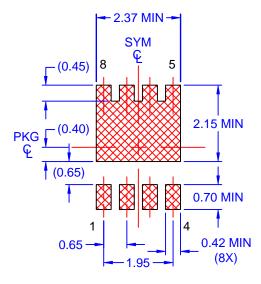


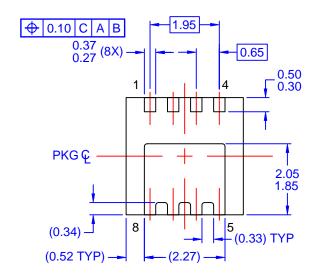
Figure 13. Junction-to-Case Transient Thermal Response Curve





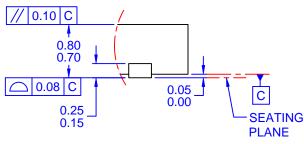


LAND PATTERN RECOMMENDATION



NOTES: UNLESS OTHERWISE SPECIFIED

- A) PACKAGE STANDARD REFERENCE: JEDEC MO-240, ISSUE A, VAR. BA, DATED OCTOBER 2002.
- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. MOLD FLASH OR BURRS DOES NOT EXCEED 0.10MM.
- D) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
- E) DRAWING FILE NAME: PQFN08HREV1



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